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QUERY CONTROL FORM		RTIS USE ONLY	
Application No. <u>091827,073</u>	Prepared by <u>NH</u>	Tracking Number <u>05914557</u>	
Examiner-GAU <u>Phan-2818</u>	Date <u>3-29-4</u>	Week Date <u>03/08/04</u>	
	No. of queries <u>1</u>	<u>IFW</u>	

JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	<u>p. PTO-1449</u>
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

MESSAGE

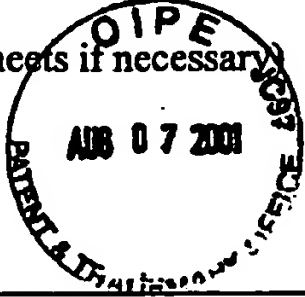
PTO-1449: Please either initial or line through citations. Copy provided for reference.

Thank you

initials NH

RESPONSE

initials

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE LIST OF PRIOR ART CITED BY APPLICANT (Use several sheets if necessary)				Atty. Docket No. YOR920000587US1 (13958)		Serial No. 09/827,073	
				RECEIVED AUG 09 2001		Applicant Louis L. Hsu et al.	
				Technology Center 2100			
Filing Date April 5, 2001				Group			
U.S. PATENT DOCUMENTS							
EXAMINE R INITIAL*	AA	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (if appropriate)
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
		"An 8ns Random Cycle Embedded RAM Macro with Dual-Port Interleaved DRAM Architecture (D ² RAM)", Yasuhiro Agata et al, 2000 IEEE International Solid-State Circuits Conference, 9 pages.					
EXAMINER				DATE CONSIDERED			
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							